

### FDB9406-VB Datasheet

# N-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ )	I <sub>D</sub> (A) <sup>a, c</sup>	Q <sub>g</sub> (Typ.)		
40	0.0017 at V <sub>GS</sub> = 10 V	150	120 nC		
	0.0025 at V <sub>GS</sub> = 4.5 V	135	120110		

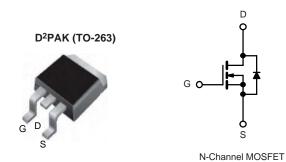
#### **FEATURES**

- Trench Power MOSFET
- 100 %  $R_g$  and UIS Tested



#### **APPLICATIONS**

- Synchronous Rectification
- Power Supplies



ABSOLUTE MAXIMUM RATINGS	<b>S</b> $T_A = 25$ °C, unles	ss otherwise not	ed		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	40	V		
Gate-Source Voltage	V <sub>GS</sub>	± 25			
	T <sub>C</sub> = 25 °C		150 <sup>a, c</sup>		
Continuous Drain Current (T. – 175 °C)	T <sub>C</sub> = 70 °C		120 <sup>c</sup>	]	
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	29 <sup>b</sup>	<u>,</u>	
	T <sub>A</sub> = 70 °C		23 <sup>b</sup>	A	
Pulsed Drain Current		I <sub>DM</sub>	380		
Avalanche Current Pulse	L = 0.1 mH	I <sub>AS</sub>	80	]	
Single Pulse Avalanche Energy	L = 0.1 mn	E <sub>AS</sub>	320	mJ	
Ocationary Course Brain Binds Coursel	T <sub>C</sub> = 25 °C	I.	110 <sup>a, c</sup>	Α	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	2.6 <sup>b</sup>	1 ^	
	T <sub>C</sub> = 25 °C		312 <sup>a</sup>		
Manianum Danian Disain ation	T <sub>C</sub> = 70 °C		200	]	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.13 <sup>b</sup>	W	
	T <sub>A</sub> = 70 °C		2.0 <sup>b</sup>		
Operating Junction and Storage Temperature Ra	ange	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient <sup>b</sup>	Steady State	R <sub>thJA</sub>	32	40	°C/W		
Maximum Junction-to-Case	Steady State	$R_{thJC}$	0.33	0.4	- C/VV		

#### Notes:

- a. Based on  $T_C$  = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. Calculated based on maximum junction temperature. Package limitation current is 110  $\,\mathrm{A.}$



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	•						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	45			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		41		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 8			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V	
Gate-Source Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$			1		
		$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α	
Drain-Source On-State Resistance <sup>a</sup>	D	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A		0.0017			
	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		0.0025		Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A		180		S	
Dynamic <sup>b</sup>				•			
Input Capacitance	C <sub>iss</sub>			9000		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		650			
Reverse Transfer Capacitance	C <sub>rss</sub>			450			
Total Gate Charge	$Q_{g}$			120	180	nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		30			
Gate-Drain Charge	Q <sub>gd</sub>			16			
Gate Resistance	$R_{g}$	f = 1 MHz		0.85	1.3	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			20	30		
Rise Time	t <sub>r</sub>	$V_{DD}$ = 20 V, $R_L$ = 1.0 $\Omega$		11	17	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		77	115		
Fall Time	t <sub>f</sub>			10	15		
Turn-On Delay Time	t <sub>d(on)</sub>			102	155		
Rise Time	t <sub>r</sub>	$V_{DD}$ = 20 V, $R_L$ = 1.0 $\Omega$		62	95		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		180	270		
Fall Time	t <sub>f</sub>			60	90		
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			110	Λ	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				200	Α	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 20 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			50	75	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 20 A, di/dt = 100 A/μs, T <sub>J</sub> = 25 °C		70	105	nC	
Reverse Recovery Fall Time	t <sub>a</sub>			30			
Reverse Recovery Rise Time	t <sub>b</sub>			20		ns	

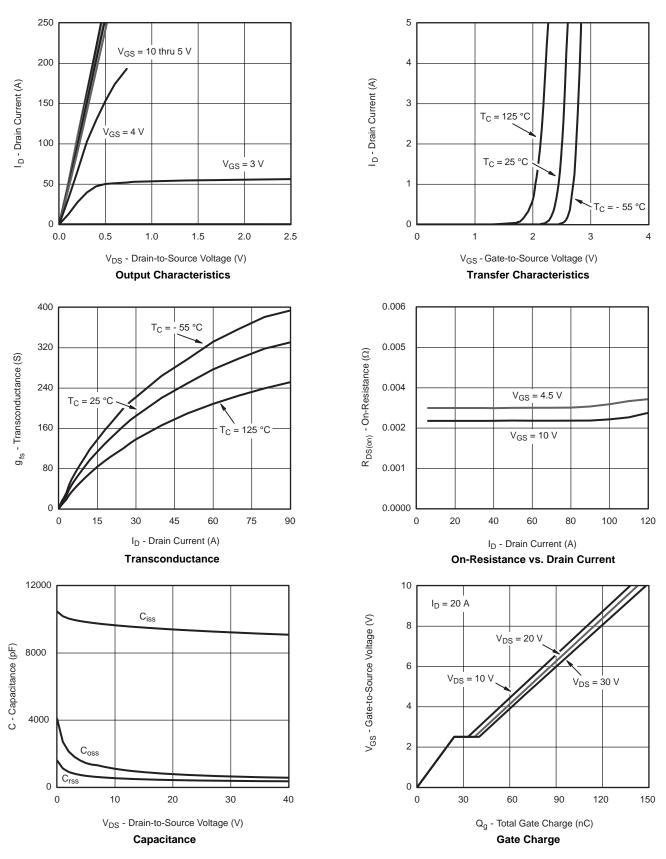
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

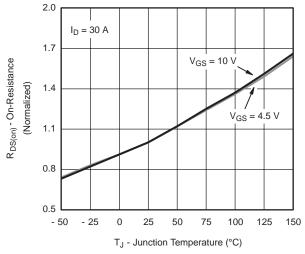


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

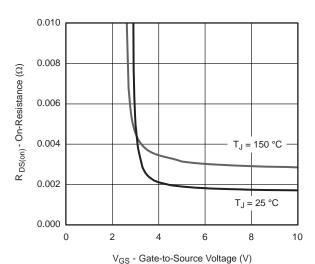




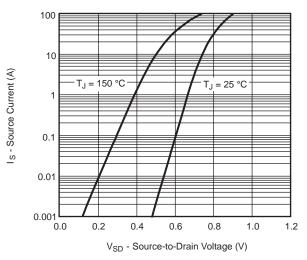
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#### On-Resistance vs. Junction Temperature



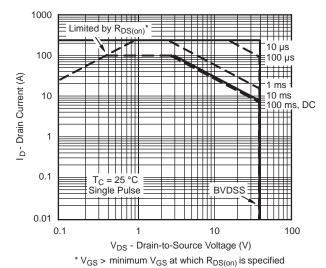
On-Resistance vs. Gate-to-Source Voltage



#### Forward Diode Voltage vs. Temperature



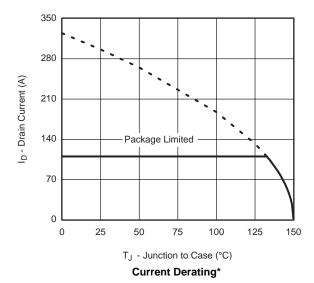
Threshold Voltage

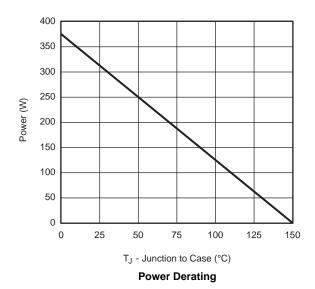


Safe Operating Area, Junction-to-Ambient

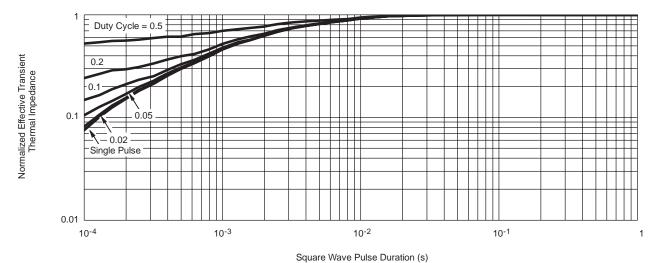


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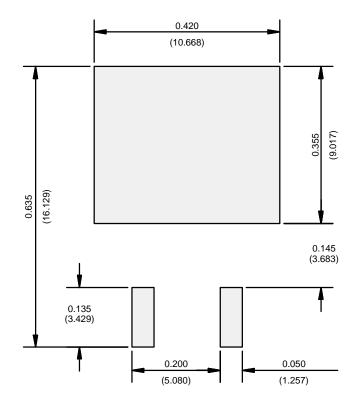
<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



### RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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